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Evolved Universal Terrestrial Radio Access (E-UTRA) and Evolved Universal Terrestrial Radio Access Network (E-UTRAN); Derivation of test tolerances for Radio Resource Management (RRM) conformance tests (3GPP TR 36.903 version 12.3.0 Release 12)



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Contents

| Intelle | ellectual Property Rights | | | | |
|--|---|------------------|--|--|--|
| Forew | vord | 2 | | | |
| Moda | l verbs terminology | 2 | | | |
| Forew | vord | 5 | | | |
| Introd | luction | 5 | | | |
| 1 | Scope | 6 | | | |
| 2 | References | 6 | | | |
| 3 3.1 3.2 | Definitions, symbols and abbreviations Definitions Symbols | 6 | | | |
| 3.3 | Abbreviations | | | | |
| 4 4.1 4.2 4.3 4.4 4.4.1 | General Principles Principle of Superposition Sensitivity analysis Statistical combination of uncertainties Correlation between uncertainties Uncorrelated uncertainties | 7 7 7 8 | | | |
| 4.4.2 | Positively correlated uncertainties | 9 | | | |
| 4.4.3 4.4.4 | Negatively correlated uncertainties Treatment of uncorrelated uncertainties | | | | |
| 4.4.5 | Treatment of positively correlated uncertainties with adverse effect | 10 | | | |
| 4.4.6 4.4.7 | Treatment of positively correlated uncertainties with beneficial effect Treatment of negatively correlated uncertainties | | | | |
| 5 | Grouping of test cases defined in TS 36.521-3 | | | | |
| 5A | Grouping of test cases defined in TS 37.571-1 | | | | |
| 6 6.1 6.2 | Determination of Test System Uncertainties General Uncertainty figures | | | | |
| 7 | Determination of Test Tolerances | | | | |
| 7.1 | General | 14 | | | |
| Anne | x A: Derivation documents | 15 | | | |
| Anne | x B:Default uncertainties for test cases defined in TS 36.521-3 | 16 | | | |
| B.0 | AWGN and Fading | 16 | | | |
| B .1 | Group A: E-UTRA Intra-frequency mobility | 16 | | | |
| B.2 | Group B: E-UTRA Inter-frequency mobility | 16 | | | |
| B.3 | Group C: E-UTRA Intra-frequency UE reporting accuracy | 17 | | | |
| B.4 | Group D: E-UTRA Inter-frequency UE reporting accuracy | 18 | | | |
| B.5 | Group E: E-UTRA Random Access | 18 | | | |
| B.6 | Group F: E-UTRA Transmit timing and Timing advance | 19 | | | |
| B.7 | Group G: E-UTRA In-sync and Out-of-sync | 20 | | | |
| B.8 | Group H: E-UTRA to UTRA Inter-RAT mobility | 20 | | | |
| B.9 | Group I: E-UTRA to GSM Inter-RAT mobility | 21 | | | |

| Annex C: | Default uncertainties for test cases defined in TS 37.571-1 | .22 |
|----------|---|-----|
| Annex D: | Change History | .23 |
| History | | .29 |

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- z the third digit is incremented when editorial only changes have been incorporated in the document.

Introduction

1 Scope

The present document specifies a general method used to derive Test Tolerances for Radio Resource Management tests, and establishes a system for relating the Test Tolerances to the measurement uncertainties of the Test System.

The test cases which have been analysed to determine Test Tolerances are included as .zip files.

The present document is applicable from Release 8 up to the release indicated on the front page of the present Terminal conformance specifications.

2 References

The following documents contain provisions which, through reference in this text, constitute provisions of the present document.

- References are either specific (identified by date of publication, edition number, version number, etc.) or non-specific.
- For a specific reference, subsequent revisions do not apply.
- For a non-specific reference, the latest version applies. In the case of a reference to a 3GPP document (including a GSM document), a non-specific reference implicitly refers to the latest version of that document *in the same Release as the present document*.

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3 Definitions, symbols and abbreviations

3.1 Definitions

For the purposes of the present document, the terms and definitions given in TR 21.905 [1] apply. A term defined in the present document takes precedence over the definition of the same term, if any, in TR 21.905 [1].

Other definitions used in the present document are listed in 3GPP TS 36.521-3 [5] or 3GPP TS 36.141 [6].

3.2 Symbols

Symbols used in the present document are listed in 3GPP TR 21.905 [1], 3GPP TS 36.521-3 [5] or 3GPP TS 36.141 [6].

3.3 Abbreviations

For the purposes of the present document, the abbreviations given in TR 21.905 [1] apply. An abbreviation defined in the present document takes precedence over the definition of the same abbreviation, if any, in TR 21.905 [1].

Other abbreviations used in the present document are listed in 3GPP TS 36.521-3 [5] or 3GPP TS 36.141 [6].

4 General Principles

4.1 Principle of Superposition

For multi-cell tests there are several cells each generating various Physical channels. In general cells are combined along with AWGN, so the signal and noise seen by the UE may be determined by more than one cell.

Since several cells may contribute towards the overall power applied to the UE, a number of test system uncertainties affect the signal and noise seen by the UE. The aim of the superposition method is to vary each controllable parameter of the test system separately, and to establish its effect on the critical parameters as seen by the UE receiver. The superposition principle then allows the effect of each test system uncertainty to be added, to calculate the overall effect.

The contributing test system uncertainties shall form a minimum set for the superposition principle to be applicable.

4.2 Sensitivity analysis

A change in any one channel level or channel ratio generated at source does not necessarily have a 1:1 effect at the UE. The effect of each controllable parameter of the test system on the critical parameters as seen by the UE receiver shall therefore be established. As a consequence of the sensitivity scaling factors not necessarily being unity, the test system uncertainties cannot be directly applied as test tolerances to the critical parameters as seen by the UE.

EXAMPLE: In many of the tests described, the $\hat{E}s / I_{ot}$ is one of the critical parameters at the UE. Scaling factors are used to model the sensitivity of the $\hat{E}s / I_{ot}$ to each test system uncertainty. When the scaling factors have been determined, the superposition principle then allows the effect of each test system uncertainty to be added, to give the overall variability in the critical parameters as seen at the UE.

There are often constraints on several parameters at the UE. The aim of the sensitivity analysis, together with the acceptable test system uncertainties, is to ensure that the variability in each of these parameters is controlled within the limits necessary for the specification to apply. The test has then been conducted under valid conditions.

4.3 Statistical combination of uncertainties

The acceptable uncertainties of the test system are specified as the measurement uncertainty tolerance interval for a specific measurement that contains 95 % of the performance of a population of test equipment, in accordance with 3GPP TS 36.521-3 [5] clause F.1. In the RRM tests covered by the present document, the Test System shall enable the stimulus signals in the test case to be adjusted to within the specified range, with an uncertainty not exceeding the specified values.

The method given in the present document combines the acceptable uncertainties of the test system, to give the overall variability in the critical parameters as seen at the UE. Since the process does not add any new uncertainties, the method of combination should be chosen to maintain the same tolerance interval for the combined uncertainty as is already specified for the contributing test system uncertainties.

The basic principle for combining uncertainties is in accordance with ETR 273-1-2 [2]. In summary, the process requires 3 steps:

- a) Express the value of each contributing uncertainty as a one standard deviation figure, from knowledge of its numeric value and its distribution.
- b) Combine all the one standard deviation figures as root-sum-squares, to give the one standard deviation value for the combined uncertainty.
- c) Expand the combined uncertainty by a coverage factor, according to the tolerance interval required.

Provided that the contributing uncertainties have already been obtained using this method, using a coverage factor of 2, further stages of combination can be achieved by performing step b) alone, since steps a) and c) simply divide by 2 and multiply by 2 respectively.

The root-sum-squares method is therefore used to maintain the same tolerance interval for the combined uncertainty as is already specified for the contributing test system uncertainties. In some cases where correlation between contributing uncertainties has an adverse effect, the method is modified in accordance with clause 4.4.5 of the present document.

In each analysis, the uncertainties are assumed to be uncorrelated, and are added result root-sum-square unless otherwise stated.

The combination of uncertainties is performed using dB values for simplicity. It has been shown that using dB uncertainty values gives a slightly worse combined uncertainty result than using linear values for the uncertainties. The analysis method therefore errs on the safe side.

4.4 Correlation between uncertainties

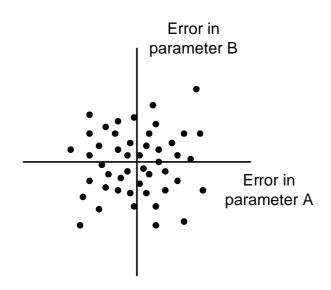
The statistical (root-sum-square) addition of uncertainties is based on the assumption that the uncertainties are independent of each other. For realisable test systems, the uncertainties may not be fully independent. The validity of the method used to add uncertainties depends on both the type of correlation and on the way in which the uncertainties affect the test requirements.

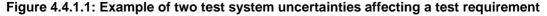
Clauses 4.4.1 to 4.4.3 give examples to illustrate different types of correlation.

Clauses 4.4.4 to 4.4.7 show how the scenarios applicable to multi-cell RRM tests are treated.

4.4.1 Uncorrelated uncertainties

The graph shows an example of two test system uncertainties, A and B, which affect a test requirement. Each sample from a population of test systems has a specific value of error in parameter A, and a specific value of error in parameter B. Each dot on the graph represents a sample from a population of test systems, and is plotted according to its error values for parameters A and B.





It can be seen that a positive value of error in parameter A, for example, is equally likely to occur with either a positive or a negative value of error in parameter B. This is expected when two parameters are uncorrelated, such as two uncertainties which arise from different and unrelated parts of the test system.

4.4.2 Positively correlated uncertainties

The graph shows an example of two test system uncertainties, A and B, which affect a test requirement. Each sample from a population of test systems has a specific value of error in parameter A, and a specific value of error in parameter B. Each dot on the graph represents a sample from a population of test systems, and is plotted according to its error values for parameters A and B.

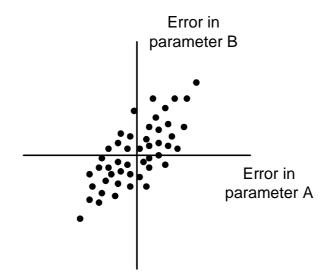


Figure 4.4.2.1: Example of two test system uncertainties affecting a test requirement

It can be seen that a positive value of error in parameter A, for example, is more likely to occur with a positive value of error in parameter B and less likely to occur with a negative value of error in parameter B. This can occur when the two uncertainties arise from similar parts of the test system, or when one component of the uncertainty affects both parameters in a similar way.

In an extreme case, if the error in parameter A and the error in parameter B came from the same sources of uncertainty, and no others, the dots would lie on a straight line of slope +1.

4.4.3 Negatively correlated uncertainties

The graph shows an example of two test system uncertainties, A and B, which affect a test condition. Each sample from a population of test systems has a specific value of error in parameter A, and a specific value of error in parameter B. Each dot on the graph represents a sample from a population of test systems, and is plotted according to its error values for parameters A and B.

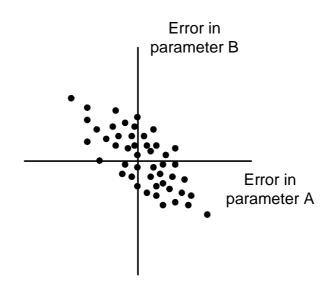


Figure 4.4.3.1: Example of two test system uncertainties affecting a test condition

It can be seen that a positive value of error in parameter A, for example, is more likely to occur with a negative value of error in parameter B and less likely to occur with a positive value of error in parameter B. This effect can theoretically occur, and is included for completeness, but is unlikely in a practical test system.

4.4.4 Treatment of uncorrelated uncertainties

If two uncertainties are uncorrelated, they are added statistically in the analysis. Provided that each uncertainty is already expressed as an expanded uncertainty with coverage factor 2, the contributing uncertainties are added root-sum-squares to give a combined uncertainty which also has coverage factor 2, and the 95% tolerance interval is maintained.

This is the default assumption.

4.4.5 Treatment of positively correlated uncertainties with adverse effect

If two test system uncertainties are positively correlated, and if they affect the value of a critical parameter in the same direction, the combined effect may be greater than predicted by adding the contributing uncertainties root-sum-squares.

In this scenario the two uncertainties are added worst-case in the analysis. Provided that each uncertainty is already expressed as an expanded uncertainty with coverage factor 2, the combined uncertainty will cover a 95% tolerance interval even when the two contributing uncertainties are fully correlated. If the two contributing uncertainties are less than fully correlated, the combined uncertainty will cover a tolerance interval greater than 95%.

4.4.6 Treatment of positively correlated uncertainties with beneficial effect

If two test system uncertainties are positively correlated, and if they affect the value of a critical parameter in opposite directions, the combined effect will be less than predicted by adding the contributing uncertainties root-sum-squares.

In this scenario the two uncertainties are added statistically in the analysis. Provided that each uncertainty is already expressed as an expanded uncertainty with coverage factor 2, the combined uncertainty will cover a 95% tolerance interval when the two contributing uncertainties are uncorrelated. If the two contributing uncertainties are positively correlated, the combined uncertainty will cover a tolerance interval greater than 95%.

4.4.7 Treatment of negatively correlated uncertainties

Negatively correlated uncertainties are excluded by the assumptions. This has been agreed as an acceptable restriction on practical test systems, as the mechanisms which produce correlation generally arise from similarities between two parts of the test system, and therefore produce positive correlation.

5 Grouping of test cases defined in TS 36.521-3

The Test cases are grouped from the viewpoint of efficiently defining the uncertainties and test tolerances. Tests in the same group generally have the same type of uncertainties, given in more detail in Annex B.

A group of test cases having significant differences from those already listed, in respect of uncertainties and test tolerance analysis, will require a new row in the Table.

| Group | E-UTRA FDD | E-UTRA TDD | E-UTRA FDD/TDD | E-UTRA FDD Inter- RAT | E-UTRA TDD Inter- RAT | Comments |
|-------|--|---|-------------------|---|--|--|
| A | 4.2.1 5.1.1 6.1.1 8.1.1 8.1.2 | 4.2.2 5.1.2 6.1.3 8.2.1 | | | | Two cell LTE intra 2 or 3 time periods Various number of sub-tests Some tests have fading |
| В | 8.1.3 4.2.3 5.1.3 5.1.5 6.1.2 8.3.1 | 8.2.2 4.2.6 5.1.4 5.1.6 6.1.4 | | | | Two or three cell LTE inter 2 or 3 time periods Some tests have fading |
| | 8.3.2 8.3.3 8.11.1 | 8.4.1 8.4.2 8.4.3 8.11.2 | | | | |
| С | 9.1.1.1 9.1.1.2 9.2.1.1 | 9.1.2.1 9.1.2.2 9.2.2.1 | | | | Two cell LTE intra 3 sub-tests RSRP, RSRQ |
| D | 9.1.3.1 9.1.3.2 9.2.3.1 9.2.3.2 | 9.1.4.1 9.1.4.2 9.2.4.1 9.2.4.2 | | | | Two cell LTE inter 2 or 3 sub-tests RSRP, RSRQ |
| E | 6.2.1 6.2.2 | 6.2.3 6.2.4 | | | | One cell LTE 1 time period Various number of sub-tests Level, timing |
| F | 7.1.1 7.2.1 | 7.1.2 7.2.2 | | | | One cell LTE Various number of time periods Various number of sub-tests Timing only |
| G | 7.3.1 7.3.2 7.3.5 7.3.6 | 7.3.3 7.3.4 7.3.7 7.3.8 | | | | One cell LTE Various number of time periods Various number of sub-tests |
| Н | | | | 4.3.1.1 4.3.1.2 4.3.1.3 4.3.2 5.2.1 5.2.5 5.2.7 | 4.3.4.2 4.3.4.1 4.3.4.3 4.3.3 5.2.2 5.2.4 5.2.10 | One cell LTE or two cell LTE inter frequency one UTRA cell Various number of time periods Various number of sub-tests Some tests have fading |
| | | | | 8.5.1 8.5.2 8.5.3 8.9.1 9.3.1 9.4.1 | 8.6.1 8.7.3 8.7.2 9.3.2 9.4.2 | |
| I | | | | 4.4.1 5.2.3 5.2.8 8.8.1 8.8.2 | 4.4.2 5.2.6 5.2.9 8.10.1 8.10.2 | One cell LTE or two cell LTE inter frequency one GSM cell 2 or 3 time periods No fading |

 Table 5-1: Test case groups for test tolerance analysis

5A Grouping of test cases defined in TS 37.571-1

The Test cases are grouped from the viewpoint of efficiently defining the uncertainties and test tolerances. Tests in the same group generally have the same type of uncertainties, given in more detail in Annex C.

A group of test cases having significant differences from those already listed, in respect of uncertainties and test tolerance analysis, will require a new row in the Table.

Table 5 A-1: Test case groups for test tolerance analysis for ECID and OTDOA positioning test cases

| Group | E-UTRA FDD | E-UTRA TDD | E-UTRA FDD/TDD | E-UTRA FDD Inter- RAT | E-UTRA TDD Inter- RAT | Comments |
|-------|---------------|---------------|-------------------|-----------------------------|-----------------------------|---|
| [FFS] | 8.1.1 | 8.1.2 | | | | One cell LTE Various number of time periods Various number of sub-tests Timing only |

Determination of Test System Uncertainties

6.1 General

6

The uncertainty of a test system when making measurements reduces the ability of the test system to distinguish between conformant and non-conformant test subjects. The aim is therefore to minimise uncertainty, subject to a number of practical constraints:

- a) A vendor"s test system should be reproducible in the required quantities.
- b) A choice of test systems should be available from different vendors.
- c) The uncertainties should allow reasonable freedom of test system implementation
- d) The test system can be run automatically
- e) The test system may include several radio access technologies
- f) It should be possible to maintain calibration of deployed test systems over reasonable spans of time and environmental conditions

In practice therefore within 3GPP the acceptable uncertainty of the test system is the smallest value that can be agreed between the test system vendors represented, consistent with the above constraints. The uncertainty will not therefore be as low as could be achieved, for example, by a national standards laboratory.

6.2 Uncertainty figures

The actual figures for the acceptable uncertainty of a test system are defined in Annex F of 36.521-3 [5] and Annex C of 37.571-1 [8]. To avoid maintenance issues with figures in separate specifications, the uncertainties are not formally defined within the present document, but informative guidelines are provided in Annex B and Annex C of the present document.

In many cases the default uncertainties in Annex B of the present document are the same as used for UTRA in TS 34.121-1 [3] to allow similar calibration methods to be used. Where E-UTRA has different requirements, or parameters are specified in a different way, the uncertainties may differ.

In some cases the default uncertainties in Annex B of the present document are the same as used for equivalent base station test specifications, which have sometimes been agreed earlier than the UE test specifications.

7 Determination of Test Tolerances

7.1 General

The general principles given in the present document are applied to each test case, according to the applicable uncertainties and requirements to obtain a correct verdict.

The test cases which have been analysed to determine Test Tolerances are included the present document as .zip files. The name of the zip file indicates the test cases covered.

Annex A gives the rationale for their inclusion.

Annex A: Derivation documents

The documents (and spreadsheets where applicable) used to derive the test tolerances for each test case are included in the present document as zip files.

The aim is to provide a reference to completed test cases, so that test tolerances for similar test cases can be derived on a common basis. The information on test case grouping in section 5 can be used to identify similarities.

Annex B: Default uncertainties for test cases defined in TS 36.521-3

This annex contains suggested uncertainties, grouped according to types of test case. The aim is to provide a consistent set of uncertainties across similar test cases to allow efficient implementation.

This Annex is informative only, as the acceptable uncertainties of a test system are defined in Annex F of 36.521-3 [5].

B.0 AWGN and Fading

The following uncertainties and parameters are suggested for E-UTRA AWGN and Fading:

Table B.0-1: Parameters for E-UTRA AWGN and Fading

| AWGN Bandwidth | ≥ 1.08MHz, 2.7MHz, 4.5MHz, 9MHz, 13.5MHz, |
|---|--|
| | 18MHz; |
| | N _{RB} x 180kHz according to BW _{Config} |
| AWGN absolute power uncertainty | Test-specific |
| AWGN flatness and signal flatness, max deviation for any Resource | ±2 dB |
| Block, relative to average over BW _{Config} | |
| AWGN peak to average ratio | ≥10 dB @0.001% |
| Signal-to noise ratio uncertainty | Test-specific |
| Fading profile power uncertainty | |
| - For 1 Tx antenna: | ±0.5 dB |
| - For 2 Tx antenna | ±0.7 dB |
| Fading profile delay uncertainty, relative to frame timing | ±5 ns (excludes absolute errors related to |
| | baseband timing) |

Values are chosen to be the same as the performance tests in section 8 of TS 36.521-1 [4].

B.1 Group A: E-UTRA Intra-frequency mobility

The following uncertainties and parameters are suggested for E-UTRA Intra-frequency mobility tests:

Table B.1-1: Maximum Test System Uncertainty for E-UTRA Intra-frequency mobility

| N _{oc} averaged over BW _{Config} | ±1.0 dB | | | |
|--|---------|--|--|--|
| Ês ₁ / N _{oc} averaged over BW _{Config} | ±0.3 dB | | | |
| Ês ₂ / N _{oc} averaged over BW _{Config} | ±0.3 dB | | | |
| Note: | | | | |
| $\hat{E}s_1 / N_{oc}$ is the ratio of cell 1 signal / AWGN | | | | |
| $\hat{E}s_2 / N_{oc}$ is the ratio of cell 2 signal / AWGN | | | | |
| For tests that use fading, the fading uncertainties are given in Table B.0.1 | | | | |

Values are chosen to be the same as equivalent parameters for UTRA in TS 34.121-1 [3].

This choice forms a minimum set, so the superposition principle can be applied.

B.2 Group B: E-UTRA Inter-frequency mobility

The following uncertainties and parameters are suggested for E-UTRA Inter-frequency mobility tests:

| N _{oc1} averaged over BW _{Config} | ±0.7 dB | | | |
|--|---------|--|--|--|
| Ês ₁ / N _{oc1} averaged over BW _{Config} | ±0.3 dB | | | |
| N _{oc2} averaged over BW _{Config} | ±0.7 dB | | | |
| Ês ₂ / N _{oc2} averaged over BW _{Config} | ±0.3 dB | | | |
| N _{oc3} averaged over BW _{Config} | ±0.7 dB | | | |
| Ês ₃ / N _{oc3} averaged over BW _{Config} | ±0.3 dB | | | |
| Note: | | | | |
| N _{oc1} is the AWGN on cell 1 frequency | | | | |
| Ês ₁ / N _{oc1} is the ratio of cell 1 signal / AWGN | | | | |
| N _{oc2} is the AWGN on cell 2 frequency | | | | |
| $\hat{E}s_2$ / N_{oc2} is the ratio of cell 2 signal / AWGN | | | | |
| N_{oc3} is the AWGN on cell 3 frequency if cell 3 exist | | | | |
| $\hat{E}s_3$ / N _{oc3} is the ratio of cell 3 signal / AWGN if cell 3 exist | | | | |
| For tests that use fading, the fading uncertainties are given in Table B.0.1 | | | | |

 Table B.2-1: Maximum Test System Uncertainty for E-UTRA Inter-frequency mobility

Noc values are chosen to be the same as the smallest existing downlink signal uncertainty in TS 36.521-1 [4].

 $\hat{E}s / N_{oc}$ values are chosen to be the same as intra-frequency in B.1.

This choice forms a minimum set, so the superposition principle can be applied.

B.3 Group C: E-UTRA Intra-frequency UE reporting accuracy

The following uncertainties and parameters are suggested for E-UTRA Intra-frequency UE reporting accuracy tests:

Table B.3-1: Maximum Test System Uncertainty for E-UTRA Intra-frequency UE reporting accuracy

| N _{oc} averaged over BW _{Config} | ±0.7 dB | |
|--|---------|--|
| N _{oc} for PRBs #22-27 | ±1.0 dB | |
| Ês ₁ / N _{oc} , Ês ₂ / N _{oc} averaged over BW _{Config} | ±0.3 dB | |
| Ês ₁ / N _{oc} , Ês ₂ / N _{oc} for PRBs #22-27 | ±0.8 dB | |
| Note: | | |
| Ês ₁ / N _{oc} is the ratio of cell 1 signal / AWGN | | |
| $\hat{E}s_2$ / N_{oc} is the ratio of cell 2 signal / AWGN | | |

In these tests the UE measures the power of Cells over specific Physical Resource Block (PRB) numbers #22 to #27. The generic AWGN parameters values similar to those used in performance tests are therefore unsuitable, because the AWGN flatness specification would allow a large deviation for the power in PRBs #22 to #27.

In addition, these tests have separate constraints on the RSRP or RSRQ reported values (derived from UE measurements over PRBs #22 to #27), and on the overall power Io, specified over BW_{Config}.

Two sets of parameters are therefore given. The set averaged over the configured bandwidth have similar values to those already proposed for other tests. The set averaged over PRBs #22 to #27 have wider values, but constraining the deviation enough not to widen the RSRP or RSRQ reporting range too much.

The N_{oc} value averaged over BW_{Config} is chosen to be the same as the smallest existing downlink signal uncertainty in TS 36.521-1 [4].

The N_{oc} value for PRBs #22-27 is chosen to allow some deviation for these specific PRBs compared to the 'averaged over BW_{Config} ' figure, but reasonably small compared to the UE reporting accuracy.

The $\hat{E}s / N_{oc}$ values averaged over BW_{Config} are chosen to be the same as intra-frequency in B.1.

The $\hat{E}s / N_{oc}$ values for PRBs #22-27 are chosen to allow some deviation for these specific PRBs compared to the 'averaged over BW_{Config}' figure, but reasonably small compared to the UE reporting accuracy.

This choice forms a minimum set (separately for PRBs #22-27, and for 'averaged over BW_{Config} '), so the superposition principle can be applied.

B.4 Group D: E-UTRA Inter-frequency UE reporting accuracy

The following uncertainties and parameters are suggested for E-UTRA Inter-frequency UE reporting accuracy tests:

Table B.4-1: Maximum Test System Uncertainty for E-UTRA Inter-frequency UE reporting accuracy

| N _{oc1} , N _{oc2} averaged over BW _{Config} | ±0.7 dB | |
|--|---------|--|
| N _{oc1} , N _{oc2} for PRBs #22-27 | ±1.0 dB | |
| Ês ₁ / N _{oc1} , Ês ₂ / N _{oc2} averaged over BW _{Config} | ±0.3 dB | |
| Ês ₁ / N _{oc1} , Ês ₂ / N _{oc2} for PRBs #22-27 | ±0.8 dB | |
| Note: | | |
| N _{oc1} is the AWGN on cell 1 frequency | | |
| $\hat{E}s_1 / N_{oc1}$ is the ratio of cell 1 signal / AWGN | | |
| Noc2 is the AWGN on cell 2 frequency | | |
| $\hat{E}s_2 / N_{oc2}$ is the ratio of cell 2 signal / AWGN | | |

In these tests the UE measures the power of Cells over specific Physical Resource Block (PRB) numbers #22 to #27. The generic AWGN parameters values similar to those used in performance tests are therefore unsuitable, because the AWGN flatness specification would allow a large deviation for the power in PRBs #22 to #27.

In addition, these tests have separate constraints on the RSRP or RSRQ reported values (derived from UE measurements over PRBs #22 to #27), and on the overall power Io, specified over BW_{Config} .

Two sets of parameters are therefore given. The set averaged over the configured bandwidth have similar values to those already proposed for other tests. The set averaged over PRBs #22 to #27 have wider values, but constraining the deviation enough not to widen the RSRP or RSRQ reporting range too much.

The N_{oc} value averaged over BW_{Config} is chosen to be the same as the smallest existing downlink signal uncertainty in TS 36.521-1 [4].

The N_{oc} value for PRBs #22-27 is chosen to allow some deviation for these specific PRBs compared to the 'averaged over BW_{Config} ' figure, but reasonably small compared to the UE reporting accuracy.

The $\hat{E}s / N_{oc}$ values averaged over BW_{Config} are chosen to be the same as inter-frequency in B.2.

The $\hat{E}s / N_{oc}$ values for PRBs #22-27 are chosen to allow some deviation for these specific PRBs compared to the 'averaged over BW_{Config}' figure, but reasonably small compared to the UE reporting accuracy.

This choice forms a minimum set (separately for PRBs #22-27, and for 'averaged over BW_{Config} '), so the superposition principle can be applied.

B.5 Group E: E-UTRA Random Access

The following uncertainties and parameters are suggested for E-UTRA Random Access tests:

| Downlink signal: | |
|---|---|
| Noc averaged over BW _{Config} | ±0.7 dB |
| Ês / N _{oc} averaged over BW _{Config} | ±0.3 dB |
| Uplink signal: | |
| Absolute power measurement | ±0.7 dB |
| Power step relative measurement | ±0.7 dB |
| Uplink signal transmit timing relative to downlink | ±3Ts |
| | $T_S = 1/(15000 \text{ x } 2048)$ seconds, the basic timing unit defined in TS 36.211 |

Table B.5-1: Maximum Test System Uncertainty for E-UTRA Random Access

The downlink N_{oc} and $\hat{E}s / N_{oc}$ values are chosen to be the same as intra-frequency in B.3. The downlink signal uncertainties are critical for random access tests because the UE uses RSRP to calculate path loss, and hence to set the uplink power to the desired value.

The uplink power absolute signal measurement uncertainty value is chosen to be the same as the Maximum Output Power test 6.2.2 in Annex F of TS 36.521-1 [4]. The uplink power relative signal measurement uncertainty value is chosen to be the same as the Relative Power control test 6.3.5.2 in Annex F of TS 36.521-1 [4].

The uncertainty for uplink signal transmit timing relative to downlink measurement was derived by taking 25% of the tightest UE core requirement, which is $12 * T_s$ for ≥ 3 MHz Channel bandwidth, giving a $\pm 3*Ts$ uncertainty.

The timing uncertainty is expressed in units of $T_s = 1 / (15000 \times 2048)$ seconds, the basic timing unit defined in TS 36.211 [7].

These choices form a minimum set, so the superposition principle can be applied.

B.6 Group F: E-UTRA Transmit timing and Timing advance

The following uncertainties and parameters are suggested for E-UTRA Transmit timing and Timing advance tests:

Table B.6-1: Maximum Test System Uncertainty for E-UTRA Transmit timing and Timing advance

| Downlink signal: | | | |
|--|--|--|--|
| N _{oc} averaged over BW _{Config} | ±3.0 dB | | |
| Ês / Noc averaged over BW _{Config} | ±0.3 dB | | |
| Uplink signal: | | | |
| Uplink signal transmit timing relative to downlink | ±3Ts | | |
| | $T_{s} = 1/(15000 \times 2048)$ seconds, the basic | | |
| | timing unit defined in TS 36.211 | | |
| Relative UE timing adjustment | ±0.5Ts | | |
| | $T_{s} = 1/(15000 \times 2048)$ seconds, the basic | | |
| | timing unit defined in TS 36.211 | | |

The downlink uncertainty values are chosen to be the same as the performance tests in section 8 of TS 36.521-1 [4]. For Transmit timing and Timing advance tests, neither the absolute level of Noc nor the signal to noise ratio is critical.

The uncertainty for uplink signal transmit timing relative to downlink measurement was derived by taking 25% of the tightest UE core requirement, which is $12 * T_s$ for ≥ 3 MHz Channel bandwidth, giving a $\pm 3*T_s$ uncertainty.

The uncertainty for relative UE timing adjustment was derived by taking 25% of the tightest UE core requirement, which is $2 * T_s$ for ≥ 10 MHz Channel bandwidth, giving a $\pm 0.5 * T_s$ uncertainty.

Both timing uncertainties are expressed in units of $T_s = 1 / (15000 \text{ x } 2048)$ seconds, the basic timing unit defined in TS 36.211 [7].

These choices form a minimum set, so the superposition principle can be applied.

B.7 Group G: E-UTRA In-sync and Out-of-sync

The following uncertainties and parameters are suggested for E-UTRA In-sync and Out-of-sync tests:

Table B.7-1: Maximum Test System Uncertainty for E-UTRA In-sync and Out-of-sync

| Downlink signal: | | | | | | |
|--|---------|--|--|--|--|--|
| Noc averaged over BW _{Config} | ±3.0 dB | | | | | |
| Ês / N _{oc} averaged over BW _{Config} | ±0.3 dB | | | | | |
| Note: | | | | | | |
| For tests that use fading, the fading uncertainties are given in Table B.0.1 | | | | | | |

Values are chosen to be the same as the performance tests in section 8 of TS 36.521-1 [4]. For In-sync and Out-of-sync tests, as with performance tests, the absolute level of Noc is not critical, but the signal to noise ratio is critical.

This choice forms a minimum set, so the superposition principle can be applied.

B.8 Group H: E-UTRA to UTRA Inter-RAT mobility

The following uncertainties and parameters are suggested for E-UTRAN cell in Table B.8-1 and for UTRAN cell in Table B.8-2.

Table B.8-1: Maximum Test System Uncertainty for E-UTRAN cell E-UTRA to UTRA Inter-RAT mobility

| N _{oc1} averaged over BW _{Config} | ±0.7 dB | | | | | |
|--|---------|--|--|--|--|--|
| Ês ₁ / N _{oc1} averaged over BW _{Config} | ±0.3 dB | | | | | |
| N _{oc2} averaged over BW _{Config} | ±0.7 dB | | | | | |
| Ês ₂ / N _{oc2} averaged over BW _{Config} | ±0.3 dB | | | | | |
| Note: | | | | | | |
| N _{oc1} is the AWGN on cell 1 frequency | | | | | | |
| Ês ₁ / N _{oc1} is the ratio of cell 1 signal / AWGN | | | | | | |
| Noc2 is the AWGN on cell 2 frequency if the second LTE cell exist | | | | | | |
| Ês ₂ / N _{oc2} is the ratio of cell 2 signal / AWGN if the second LTE cell exist | | | | | | |
| For cells that use fading, the fading uncertainties are given in Table B.0.1 | | | | | | |

Table B.8-2: Maximum Test System Uncertainty for UTRAN cell E-UTRA to UTRA Inter-RAT mobility

| l _{oc} | ±0.7 dB | | | | | | |
|--|------------------------|--|--|--|--|--|--|
| I _{or} / I _{oc} | ±0.3 dB | | | | | | |
| E _c / I _{or} | | | | | | | |
| CPICH E _c / I _{or} (UTRA FDD) | ±0.1dB | | | | | | |
| PCCPCH E _c / I _{or} (UTRA TDD) | ±0.1dB | | | | | | |
| DwPCH E _c / I _{or} (UTRA TDD) | ±0.1dB | | | | | | |
| Note: | | | | | | | |
| I _{oc} is the AWGN on UTRA cell frequency | | | | | | | |
| I _{or} / I _{oc} is the ratio of UTRA cell signal / AWGN | | | | | | | |
| CPICH E _c / I _{or} is the fraction of UTRA FDD cell power assigned to the | | | | | | | |
| PCCPCH E _c / I _{or} is the fraction of UTRA TDD cell power assigned to the PCCPCH Physical channel | | | | | | | |
| DwPCH_Ec/lor is the fraction of UTRA TDD cell power assigned to the DwPCH channel | | | | | | | |
| For cell that use fading, .the fading profile power uncertainty of ±0.5 d | B shall be considered. | | | | | | |

 $\hat{E}s$ / Noc and $\hat{I}or$ / Ioc are chosen to be similar to equivalent parameters in W-CDMA. The absolute levels of Noc and Ioc are specified as ± 0.7 dB, similar to the uncertainty for other absolute power values such as RefSens. The Ec / Ior is specified as ± 0.1 dB, similar to the uncertainty in TS 34.121-1.

This choice forms a minimum set, so the superposition principle can be applied.

B.9 Group I: E-UTRA to GSM Inter-RAT mobility

The following uncertainties and parameters are suggested for E-UTRAN cell in Table B.9-1 and for GSM cell in Table B.9-2.

Table B.9-1: Maximum Test System Uncertainty for E-UTRAN cell E-UTRA to GSM Inter-RAT mobility

| N _{oc1} averaged over BW _{Config} | ±0.7 dB | | | | | |
|---|-----------------------|--|--|--|--|--|
| Ês ₁ / N _{oc1} averaged over BW _{Config} | ±0.3 dB | | | | | |
| N _{oc2} averaged over BW _{Config} | ±0.7 dB | | | | | |
| Ês ₂ / N _{oc2} averaged over BW _{Config} | ±0.3 dB | | | | | |
| Note: | | | | | | |
| N _{oc1} is the AWGN on cell 1 frequency | | | | | | |
| Ês ₁ / N _{oc1} is the ratio of cell 1 signal / AWGN | | | | | | |
| Noc2 is the AWGN on cell 2 frequency if the second LTE cell exist | | | | | | |
| $\hat{E}s_2 / N_{oc2}$ is the ratio of cell 2 signal / AWGN if the | second LTE cell exist | | | | | |

Table B.9-2: Maximum Test System Uncertainty for UTRAN cell E-UTRA to GSM Inter-RAT mobility

| Signal level | ±0.7 dB | |
|---|---------|--|
| Note: | | |
| GSM cell has only the wanted signal, without AWGN | | |

 N_{oc} values are chosen to be the same as the smallest existing downlink signal uncertainty in TS 36.521-1 [4].

 $\hat{E}s / N_{oc}$ values are chosen to be the same as intra-frequency in B.1.

The GSM cell signal level is specified as ± 0.7 dB, similar to the uncertainty for other absolute power values such as E-UTRA RefSens.

This choice forms a minimum set, so the superposition principle can be applied.

Annex C: Default uncertainties for test cases defined in TS 37.571-1

This annex contains suggested uncertainties, grouped according to types of test case. The aim is to provide a consistent set of uncertainties across similar test cases to allow efficient implementation.

This Annex is informative only, as the acceptable uncertainties of a test system are defined in Annex C of 37.571-1 [8].

Annex D: Change History

| Date | TSG # | TSG Doc. | CR | R ev | Subject/Comment | Old | New |
|---------|-----------------|-----------|------|---------|--|-------|-------|
| 2010-02 | RAN5#46 | R5-072185 | - | - | TR 36.903 Skeleton proposed for RAN5#46 | - | 0.0.1 |
| 2010-06 | - | - | - | - | TR 36.903 update proposed | 0.0.1 | 0.0.x |
| 2010-08 | RAN5#48 | - | - | - | TR 36.903 update proposed | 0.0.x | 0.0.2 |
| 2010-08 | RAN5#48 | R5-104409 | - | - | TR 36.903 update proposed including all docs agreed on RAN5#48 | 0.0.2 | 0.1.0 |
| 2010-09 | - | - | - | - | Small editorial corrections | 0.1.0 | 0.1.1 |
| 2010-09 | RAN5#49 | R5-106802 | - | - | TR 36.903 update proposed including all docs agreed on RAN5#49 | 0.1.1 | 1.0.0 |
| 2010-12 | RAN5#50 | R5-101182 | - | - | TR 36.903 v1.0.0 on Derivation of test tolerances for multi-cell RRM conformance tests (Approval) | 1.0.0 | 8.0.0 |
| 2010-12 | RAN5#50 | - | - | - | Raised to v9.0.0 with no change | 8.0.0 | 9.0.0 |
| 2011-09 | RAN5#52 | R5-113225 | 0001 | - | Test Tolerance analysis for RRM test case 4.3.1.3 | 9.0.0 | 9.1.0 |
| 2011-09 | RAN5#52 | R5-113227 | 0002 | - | RRM Test Tools agreed at RAN5#50 in TR 36.903 | 9.0.0 | 9.1.0 |
| 2011-09 | RAN5#52 | R5-113228 | 0003 | - | RRM Test Tools agreed at RAN5#51 in TR 36.903 | 9.0.0 | 9.1.0 |
| 2011-09 | RAN5#52 | R5-113248 | 0004 | - | Add Test Tolerance analysis for the inter RAT E-UTRAN | 9.0.0 | 9.1.0 |
| 2011-09 | RAN5#52 | R5-114008 | 0005 | - | handover test cases 5.2.1 and 5.2.2 Add Test Tolerance analysis for E-UTRAN to UTRA TDD | 9.0.0 | 9.1.0 |
| | D 4 1 1 2 1 2 2 | | | | handover test case 5.2.4 | | |
| 2011-09 | RAN5#52 | R5-114010 | 0006 | - | RRM Test Tools Updates agreed at RAN5#50 for TR 36.903 | 9.0.0 | 9.1.0 |
| 2011-09 | RAN5#52 | R5-114011 | 0007 | - | Update Test Tolerance analysis for Test cases 8.x | 9.0.0 | 9.1.0 |
| 2011-09 | RAN5#52 | R5-114012 | 8000 | - | Test Tolerance analysis for TS36.521-3 FDD SON ANR test case 8.5.2 | 9.0.0 | 9.1.0 |
| 2011-09 | RAN5#52 | R5-114015 | 0009 | - | Add Test Tolerance analysis for E-UTRAN FDD/TDD - UTRA FDD CPICH Ec/No absolute measurement accuracy test cases | 9.0.0 | 9.1.0 |
| 2011-09 | RAN5#52 | R5-114017 | 0010 | - | Add Test Tolerance analysis for E-UTRAN FDD- UTRAN TDD event triggered reporting under fading propagation conditions | 9.0.0 | 9.1.0 |
| 2011-09 | RAN5#52 | R5-114018 | 0011 | - | Update analysis for TC 8.3.3+8.4.3 in 36.903 | 9.0.0 | 9.1.0 |
| 2011-09 | RAN5#52 | R5-114020 | 0012 | - | Add Uncertainties and TT analysis for TC 4.3.4.3 in 36.903 | 9.0.0 | 9.1.0 |
| 2011-09 | RAN5#52 | R5-114058 | 0013 | - | Add Test Tolerance analysis for E-UTRAN to UTRA Cell Re- Selection test cases 4.3.4.1 | 9.0.0 | 9.1.0 |
| 2011-12 | RAN5#53 | R5-115149 | 0014 | - | Add Inter-RAT test case groups in 36.903 | 9.1.0 | 9.2.0 |
| 2011-12 | RAN5#53 | R5-115825 | 0015 | - | Test tolerances methodology for UE measurement procedures Inter-RAT event triggered reporting when DRX is used under fading test case 8.5.3 in TR 36.903 | 9.1.0 | 9.2.0 |
| 2011-12 | RAN5#53 | R5-115188 | 0016 | - | Test Tolerance analysis for RRM test case 8.11.3 | 9.1.0 | 9.2.0 |
| 2011-12 | RAN5#53 | R5-115201 | 0017 | - | Test Tolerance analysis for TS36.521-3 TDD SON ANR test case 8.7.3 | 9.1.0 | 9.2.0 |
| 2011-12 | RAN5#53 | R5-115402 | 0018 | - | Test Tolerance analysis for RRM test case 4.3.3 | 9.1.0 | 9.2.0 |
| 2011-12 | RAN5#53 | R5-115788 | 0019 | - | GCF Priority 2 - Add RRM Test Tolerance analysis for RRM test case 8.11.1 and 8.11.2 | 9.1.0 | 9.2.0 |
| 2011-12 | RAN5#53 | R5-115826 | 0020 | - | Update of Test Tolerances analysis for ch.9 test cases | 9.1.0 | 9.2.0 |
| 2011-12 | RAN5#53 | R5-115898 | 0021 | - | Add test tolerance analysis for 6.1.3 and 6.1.4 | 9.1.0 | 9.2.0 |
| 2012-03 | RAN5#54 | R5-120108 | 0022 | - | Test Tolerance analysis for TS36.521-3 TDD new CGI test cases 8.2.3 and 8.2.4 | 9.2.0 | 9.3.0 |
| 2012-03 | RAN5#54 | R5-120123 | 0023 | - | Test Tolerance analysis for TS36.521-3 TDD Inter-frequency new CGI test cases 8.4.4 and 8.4.5. | 9.2.0 | 9.3.0 |
| 2012-03 | RAN5#54 | R5-120246 | 0024 | - | Update Test Tolerance analysis for RRM test cases 9.1.4.1 and 9.1.4.2 | 9.2.0 | 9.3.0 |
| 2012-03 | RAN5#54 | R5-120247 | 0025 | - | Update RRM Test Tolerance analysis for TDD PRACH Test cases 6.2.3+6.2.4 | 9.2.0 | 9.3.0 |
| 2012-03 | RAN5#54 | R5-120248 | 0026 | - | Add Test Tolerance analysis for RRM test case 8.11.4 | 9.2.0 | 9.3.0 |
| 2012-03 | RAN5#54 | R5-120906 | 0027 | - | Add TT Analysis for TC 4.5.1.1 in 36.903 | 9.2.0 | 9.3.0 |
| 2012-03 | RAN5#54 | R5-120916 | 0028 | - | Add TT Analysis for TC 5.3.1 in 36.903 | 9.2.0 | 9.3.0 |
| 2012-06 | RAN5#55 | R5-121246 | 0029 | - | Grouping of positioning test cases in TR36.903 | 9.3.0 | 9.4.0 |
| 2012-06 | RAN5#55 | R5-121606 | 0030 | - | Add Test Tolerance analysis for RRM test cases 4.2.4 and 4.2.5 | 9.3.0 | 9.4.0 |

| 2012-06 | RAN5#55 | R5-121608 | 0031 | - | Add Test Tolerance analysis for RRM test cases 5.1.7 and 5.1.8 | 9.3.0 | 9.4.0 |
|---------|---------|-----------|------|---|--|-------|-------|
| 2012-06 | RAN5#55 | R5-121610 | 0032 | - | Add Test Tolerance analysis for RRM test cases 8.14.1 | 9.3.0 | 9.4.0 |
| 2012-06 | RAN5#55 | R5-121612 | 0033 | - | Add Test Tolerance analysis for RRM test cases 8.15.1 | 9.3.0 | 9.4.0 |
| 2012-06 | RAN5#55 | R5-121614 | 0034 | - | Add Test Tolerance analysis for RRM test case 9.1.5.1 | 9.3.0 | 9.4.0 |
| 2012-06 | RAN5#55 | R5-121616 | 0035 | - | Addition of Test Tolerance analysis for FDD - TDD Inter Frequency Relative Accuracy of RSRP test case 9.1.5.2 | 9.3.0 | 9.4.0 |
| 2012-06 | RAN5#55 | R5-121926 | 0036 | - | TT 9.6.2 analysis for 36.903 | 9.3.0 | 9.4.0 |
| 2012-06 | RAN5#55 | R5-121928 | 0037 | - | Resubmission of TT Analysis for TC 4.5.1.1 in 36.903 | 9.3.0 | 9.4.0 |
| 2012-06 | RAN5#55 | - | - | - | Added two missing TT Analysis zip files | 9.4.0 | 9.4.1 |
| 2012-09 | RAN5#56 | R5-123213 | 0045 | - | Add Test Tolerance analyses for TS 36.521-3 Test cases 4.2.7 and 4.2.8 | 9.4.1 | 9.5.0 |
| 2012-09 | RAN5#56 | R5-123921 | 0038 | - | Update Test Tolerance analysis for RRM test case 9.1.2.1 | 9.4.1 | 9.5.0 |
| 2012-09 | RAN5#56 | R5-123922 | 0039 | - | Update Test Tolerance analysis for RRM test case 9.1.2.2 | 9.4.1 | 9.5.0 |

| 2012-09 | RAN5#56 | R5-123923 | 0040 | - | Update Test Tolerance analysis for RRM test cases 9.1.3.1+9.1.4.1 | 9.4.1 | 9.5.0 |
|---------|---------|-----------|------|---|--|--------|--------|
| 2012-09 | RAN5#56 | R5-123924 | 0041 | - | Update Test Tolerance analysis for RRM test cases 9.1.3.2+9.1.4.2 | 9.4.1 | 9.5.0 |
| 2012-09 | RAN5#56 | R5-123925 | 0042 | - | Update Test Tolerance analysis for RRM test cases 9.2.1.1+9.2.2.1 | 9.4.1 | 9.5.0 |
| 2012-09 | RAN5#56 | R5-123926 | 0043 | - | Update Test Tolerance analysis for RRM test cases 9.2.3.1+9.2.4.1 | 9.4.1 | 9.5.0 |
| 2012-09 | RAN5#56 | R5-123927 | 0044 | - | Update Test Tolerance analysis for RRM test cases 9.2.3.2+9.2.4.2 | 9.4.1 | 9.5.0 |
| 2012-12 | RAN5#57 | R5-125558 | 0048 | - | Addition of uncertainties and test tolerance definition and analysis for TC 9.2.4A.1 | 9.5.0 | 9.6.0 |
| 2012-12 | RAN5#57 | R5-125815 | 0049 | - | Addition of uncertainties and test tolerance definition and analysis for TC 4.5.2.1 | 9.5.0 | 9.6.0 |
| 2012-12 | RAN5#57 | R5-125816 | 0050 | - | Addition of uncertainties and test tolerance definition and analysis for TC 5.3.5 | 9.5.0 | 9.6.0 |
| 2012-12 | RAN5#57 | R5-125817 | 0051 | - | Addition of uncertainties and test tolerance definition and analysis for TC 8.14.2 | 9.5.0 | 9.6.0 |
| 2012-12 | RAN5#57 | R5-125818 | 0052 | - | Addition of uncertainties and test tolerance definition and analysis for TC 8.15.2 | 9.5.0 | 9.6.0 |
| 2012-12 | RAN5#57 | R5-125819 | 0053 | - | Addition of uncertainties and test tolerance definition and analysis for TC 8.14.3 and 8.15.3 | 9.5.0 | 9.6.0 |
| 2012-12 | RAN5#57 | R5-125820 | 0054 | - | Addition of uncertainties and test tolerance definition and analysis for TC 9.2.4A.2 | 9.5.0 | 9.6.0 |
| 2012-12 | RAN5#57 | R5-125356 | 0046 | - | Add Test Tolerance analyses for TS 36.521-3 Test cases 8.16.1 and 8.16.2 | 9.6.0 | 10.0.0 |
| 2012-12 | RAN5#57 | R5-125362 | 0047 | - | Update TS 36.521-3 Test cases 5.2.3+5.2.6 Test Tolerance analyses for >3GHz | 9.6.0 | 10.0.0 |
| 2013-03 | RAN5#58 | R5-130055 | 0055 | - | Update TS 36.521-3 Test cases 7.1.1+7.1.2 Test Tolerance analyses | 10.0.0 | 10.1.0 |
| 2013-03 | RAN5#58 | R5-130057 | 0056 | - | Add Test Tolerance analyses for TS 36.521-3 Test cases 9.1.6.1 and 9.1.7.1 | 10.0.0 | 10.1.0 |
| 2013-03 | RAN5#58 | R5-130059 | 0057 | - | Add Test Tolerance analyses for TS 36.521-3 Test cases 9.1.6.2 and 9.1.7.2 | 10.0.0 | 10.1.0 |
| 2013-03 | RAN5#58 | R5-130061 | 0058 | - | Add Test Tolerance analyses for TS 36.521-3 Test cases 9.2.5.1 and 9.2.6.1 | 10.0.0 | 10.1.0 |
| 2013-03 | RAN5#58 | R5-130063 | 0059 | - | Add Test Tolerance analyses for TS 36.521-3 Test cases 9.2.5.2 and 9.2.6.2 | 10.0.0 | 10.1.0 |
| 2013-03 | RAN5#58 | R5-130393 | 0061 | - | Addition of test tolerance analysis for TCs 6.3.1+6.3.9 | 10.0.0 | 10.1.0 |
| 2013-03 | RAN5#58 | R5-130394 | 0062 | - | Addition of test tolerance analysis for TCs 6.3.3+6.3.10 | 10.0.0 | 10.1.0 |
| 2013-03 | RAN5#58 | R5-130933 | 0063 | - | Addition of uncertainties and test tolerance definition and analysis for TC 8.16.3 and TC 8.16.4 | 10.0.0 | 10.1.0 |
| 2013-06 | RAN5#59 | R5-131179 | 0077 | - | RRM: Add test tolerance analyses for TCs 8.1.5 and 8.1.6 | 10.1.0 | 10.2.0 |
| 2013-06 | RAN5#59 | R5-131181 | 0065 | - | RRM: Add test tolerance analyses for TCs 8.3.4 and 8.3.5 | 10.1.0 | 10.2.0 |
| 2013-06 | RAN5#59 | R5-131279 | 0066 | - | Add Test Tolerance analyses for TS 36.521-3 Test cases 9.2.7.1, 9.2.8.1 | 10.1.0 | 10.2.0 |
| 2013-06 | RAN5#59 | R5-131285 | 0067 | - | Add Test Tolerance analyses for TS 36.521-3 Test cases 8.11.5, 8.11.6 | 10.1.0 | 10.2.0 |

| 2013-06 | RAN5#59 | R5-131287 | 0068 | - | Add Test Tolerance analyses for TS 36.521-3 Test cases | 10.1.0 | 10.2.0 |
|---------|---------|-----------|------|---|---|--------|--------|
| 0040.00 | DANE | DE 404000 | 0000 | | 9.5.1, 9.5.2 | 10.1.0 | 10.0.0 |
| 2013-06 | RAN5#59 | R5-131290 | 0069 | - | Remove superseded analysis zip files | 10.1.0 | |
| 2013-06 | RAN5#59 | R5-131400 | 0070 | - | Test Tolerance analyses for TS 36.521-3 test cases 5.2.4 and 5.2.5 | 10.1.0 | 10.2.0 |
| 2013-06 | RAN5#59 | R5-131401 | 0071 | - | Test Tolerance analyses for TS 36.521-3 test case 8.5.4 | 10.1.0 | 10.2.0 |
| 2013-06 | RAN5#59 | R5-131402 | 0072 | - | Test Tolerance analyses for TS 36.521-3 test cases 8.7.4 and 8.9.2 | 10.1.0 | 10.2.0 |
| 2013-06 | RAN5#59 | R5-131461 | 0073 | - | Addition of test tolerance analysis for TCs 6.3.2+6.3.12 | 10.1.0 | 10.2.0 |
| 2013-06 | RAN5#59 | R5-131464 | 0074 | - | Addition of test tolerance analysis for TCs 6.3.4+6.3.11 | 10.1.0 | 10.2.0 |
| 2013-06 | RAN5#59 | R5-131467 | 0075 | - | Addition of test tolerance analysis for TCs 6.3.5+6.3.6+6.3.7+6.3.8 | 10.1.0 | 10.2.0 |
| 2013-09 | RAN5#60 | R5-133100 | 0078 | - | Add Test Tolerance analyses for TS 36.521-3 Test cases 9.1.8.1+9.1.9.1 | 10.2.0 | 10.3.0 |
| 2013-09 | RAN5#60 | R5-133102 | 0079 | - | Add Test Tolerance analyses for TS 36.521-3 Test cases 9.1.8.2+9.1.9.2 | 10.2.0 | 10.3.0 |
| 2013-09 | RAN5#60 | R5-133104 | 0080 | - | Update Test Tolerance analyses for TS 36.521-3 Test cases 9.1.3.x and 9.1.4.x | 10.2.0 | 10.3.0 |
| 2013-09 | RAN5#60 | R5-133106 | 0081 | - | Test Tolerances update for eICIC absolute RSRQ Test cases 9.2.7.1+9.2.8.1 | 10.2.0 | 10.3.0 |
| 2013-09 | RAN5#60 | R5-133219 | 0082 | - | RRM: Test tolerance analyses for TCs 9.6.1 and 9.6.2 | 10.2.0 | 10.3.0 |
| 2013-09 | RAN5#60 | R5-133349 | 0083 | - | Update Test Tolerance analyses for TS 36.521-3 Test cases 9.1.1.1 and 9.1.2.1 | 10.2.0 | 10.3.0 |
| 2013-09 | RAN5#60 | R5-133374 | 0084 | - | Add Test Tolerance Analyses for TS 37.571-1 Test Cases 9.1.1 and 9.1.2 | 10.2.0 | 10.3.0 |
| 2013-09 | RAN5#60 | R5-133376 | 0085 | - | Add Test Tolerance Analyses for TS 37.571-1 Test Cases 9.1.3 and 9.1.4 | 10.2.0 | 10.3.0 |
| 2013-09 | RAN5#60 | R5-133843 | 0086 | - | LBS Perf: Test tolerance analyses for TCs 8.1.1 and 8.1.2 | 10.2.0 | 10.3.0 |
| 2013-12 | RAN5#61 | R5-134144 | 0087 | - | Add Test Tolerance analyses for TS 36.521-3 Test cases 9.1.12.1 and 9.1.13.1 | 10.3.0 | 10.4.0 |
| 2013-12 | RAN5#61 | R5-134146 | 0088 | - | Add Test Tolerance analyses for TS 36.521-3 Test cases 9.1.12.2 and 9.1.13.2 | 10.3.0 | 10.4.0 |
| 2013-12 | RAN5#61 | R5-134148 | 0089 | - | Add Test Tolerance analyses for TS 36.521-3 Test cases 9.2.11.1 and 9.2.12.1 | 10.3.0 | 10.4.0 |
| 2013-12 | RAN5#61 | R5-134150 | 0090 | - | Add Test Tolerance analyses for TS 36.521-3 Test cases 9.2.11.2 and 9.2.12.2 | 10.3.0 | 10.4.0 |
| 2013-12 | RAN5#61 | R5-134220 | 0091 | - | Add Test Tolerance analysis for TS 36.521-3 Test case 8.20.3 | 10.3.0 | 10.4.0 |
| 2013-12 | RAN5#61 | R5-134222 | 0092 | - | Add Test Tolerance analysis for TS 36.521-3 Test cases 9.2.9.1 and 9.2.10.1 | 10.3.0 | 10.4.0 |
| 2013-12 | RAN5#61 | R5-135015 | 0093 | - | Add Test Tolerance Analyses for TS 37.571-1 Test Cases 9.2.1 and 9.2.2 | 10.3.0 | 10.4.0 |
| 2013-12 | RAN5#61 | R5-135017 | 0094 | - | Add Test Tolerance Analyses for TS 37.571-1 Test Cases 9.2.4 and 9.2.5 | 10.3.0 | 10.4.0 |
| 2013-12 | RAN5#61 | - | - | - | Upgraded to Rel-11 with no change | 10.4.0 | 11.0.0 |
| 2013-12 | RAN5#61 | R5-134215 | 0108 | - | Add Test Tolerance analyses for TS 36.521-3 Test case 9.1.17.1 | 11.0.0 | 12.0.0 |
| 2013-12 | RAN5#61 | R5-134217 | 0109 | - | Add Test Tolerance analyses for TS 36.521-3 Test case | 11.0.0 | 12.0.0 |

| | | | | | 9.2.17.1 and update 9.2.1.1+9.2.2.1 | | |
|---------|---------|-----------|------|---|--|--------|--------|
| 2013-12 | RAN5#61 | R5-134611 | 0102 | - | Add Test Tolerance analyses for TS 36.521-3 Test case 7.2.3 | 11.0.0 | 12.0.0 |
| 2013-12 | RAN5#61 | R5-135050 | 0095 | - | Add Test Tolerance analyses for TS 36.521-3 Test case 4.2.9 and update 4.2.1+4.2.2 | 11.0.0 | 12.0.0 |
| 2013-12 | RAN5#61 | R5-135051 | 0096 | - | Add Test Tolerance analyses for TS 36.521-3 Test case 4.3.1.4 and update 4.3.1.2+4.3.3 | 11.0.0 | 12.0.0 |
| 2013-12 | RAN5#61 | R5-135052 | 0097 | - | Add Test Tolerance analyses for TS 36.521-3 Test case 5.1.9 and update 5.1.1+5.1.2 | 11.0.0 | 12.0.0 |
| 2013-12 | RAN5#61 | R5-135053 | 0098 | - | Add Test Tolerance analyses for TS 36.521-3 Test case 5.2.11 and update 5.2.1+5.2.2 | 11.0.0 | 12.0.0 |
| 2013-12 | RAN5#61 | R5-135054 | 0099 | - | Add Test Tolerance analyses for TS 36.521-3 Test case 6.1.5 and update 6.1.1+6.1.3 | 11.0.0 | 12.0.0 |
| 2013-12 | RAN5#61 | R5-135055 | 0100 | - | Add Test Tolerance analyses for TS 36.521-3 Test case 6.2.5 | 11.0.0 | 12.0.0 |
| 2013-12 | RAN5#61 | R5-135056 | 0101 | - | Add Test Tolerance analyses for TS 36.521-3 Test case 6.2.6 | 11.0.0 | 12.0.0 |
| 2013-12 | RAN5#61 | R5-135058 | 0103 | - | Add Test Tolerance analyses for TS 36.521-3 Test case 7.3.23 | 11.0.0 | 12.0.0 |
| 2013-12 | RAN5#61 | R5-135059 | 0104 | - | Add Test Tolerance analyses for TS 36.521-3 Test case 7.3.25 | 11.0.0 | 12.0.0 |
| 2013-12 | RAN5#61 | R5-135060 | 0105 | - | Add Test Tolerance analyses for TS 36.521-3 Test case 8.1.9 | 11.0.0 | 12.0.0 |
| 2013-12 | RAN5#61 | R5-135061 | 0106 | - | Add Test Tolerance analyses for TS 36.521-3 Test case 8.1.10 | 11.0.0 | 12.0.0 |
| 2013-12 | RAN5#61 | R5-135062 | 0107 | - | Add Test Tolerance analyses for TS 36.521-3 Test case 8.5.7 | 11.0.0 | 12.0.0 |
| 2014-03 | RAN5#62 | R5-140083 | 0110 | - | Add Test Tolerance analyses for TS 36.521-3 Test cases 8.20.1 and 8.20.2 | 12.0.0 | 12.1.0 |
| 2014-03 | RAN5#62 | R5-140233 | 0113 | - | Add Test Tolerance analyses for TS 36.521-3 Test case 9.1.16.2 and update 9.1.1.2+9.1.2.2 | 12.0.0 | 12.1.0 |
| 2014-03 | RAN5#62 | R5-140235 | 0114 | - | Add Test Tolerance analyses for TS 36.521-3 Test case 9.1.18.1 and update 9.2.3.1+9.2.4.1 | 12.0.0 | 12.1.0 |
| 2014-03 | RAN5#62 | R5-140237 | 0115 | - | Add Test Tolerance analyses for TS 36.521-3 Test case 9.1.18.2 and update 9.2.3.2+9.2.4.2 | 12.0.0 | 12.1.0 |
| 2014-03 | RAN5#62 | R5-140239 | 0116 | - | Add Test Tolerance analysis for TS 36.521-3 Test case 8.20.4 | 12.0.0 | 12.1.0 |
| 2014-03 | RAN5#62 | R5-140288 | 0118 | - | Addition of test tolerance analysis for TC 7.3.24 | 12.0.0 | 12.1.0 |
| 2014-03 | RAN5#62 | R5-140292 | 0119 | - | Addition of test tolerance analysis for TC 9.1.17.2 | 12.0.0 | 12.1.0 |
| 2014-03 | RAN5#62 | R5-140294 | 0120 | - | Addition of test tolerance analysis for TC 9.3.3 | 12.0.0 | 12.1.0 |
| 2014-03 | RAN5#62 | R5-140296 | 0121 | - | Addition of test tolerance analysis for TC 9.4.3 | 12.0.0 | 12.1.0 |
| 2014-03 | RAN5#62 | R5-140864 | 0122 | - | Addition of test tolerance analysis for TC 9.1.16.1 | 12.0.0 | 12.1.0 |
| 2014-03 | RAN5#62 | R5-141051 | 0117 | - | Addition of test tolerance analysis for TC 7.1.5 | 12.0.0 | 12.1.0 |
| 2014-06 | RAN5#63 | R5-142373 | 0123 | - | Update Test Tolerance analyses for TS 36.521-3 Test cases 9.1.8.1+9.1.9.1 | 12.1.0 | 12.2.0 |
| 2014-06 | RAN5#63 | R5-142377 | 0124 | - | Update Test Tolerance analyses for TS 36.521-3 Test cases 9.1.8.2+9.1.9.2 | 12.1.0 | 12.2.0 |
| 2014-06 | RAN5#63 | R5-142381 | 0125 | - | Update Test Tolerance analyses for TS 36.521-3 Test cases 9.2.7.1+9.2.8.1 | 12.1.0 | 12.2.0 |
| 2014-06 | RAN5#63 | R5-142545 | 0126 | - | Add Test Tolerance analyses for TS 36.521-3 Test cases 8.1.7 and 8.2.5 | 12.1.0 | 12.2.0 |
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| 2014-06 | RAN5#63 | R5-142552 | 0127 | - | Add Test Tolerance analyses for TS 36.521-3 Test cases 7.3.11,7.3.12,7.3.15 and 7.3.16 | 12.1.0 | 12.2.0 |
|---------|---------|-----------|------|---|--|--------|--------|
| 2014-06 | RAN5#63 | R5-142712 | 0128 | - | Test Tolerance analysis for eICIC RRM TC 9.1.10.1, 9.1.11.1 | 12.1.0 | 12.2.0 |
| 2014-06 | RAN5#63 | R5-142751 | 0129 | - | Update Test Tolerance analyses for TS 36.521-3 Test cases 9.2.9.1+9.2.10.1 | 12.1.0 | 12.2.0 |
| 2014-06 | RAN5#63 | R5-142763 | 0130 | - | Addition of test tolerance analysis for 36.521-3 test case 9.1.10.2, 9.1.11.2 | 12.1.0 | 12.2.0 |
| 2014-06 | RAN5#63 | R5-143021 | 0131 | - | Add Test Tolerance analyses for TS 36.521-3 Test cases 7.3.9,7.3.10,7.3.13 and 7.3.14 | 12.1.0 | 12.2.0 |
| 2014-09 | RAN5#64 | R5-144126 | 0132 | - | Add Test Tolerance analyses for TS 36.521-3 Test cases 8.16.5 and 8.16.6 | 12.2.0 | 12.3.0 |
| 2014-09 | RAN5#64 | R5-144128 | 0133 | - | Add Test Tolerance analyses for TS 36.521-3 Test cases 8.16.7 and 8.16.8 | 12.2.0 | 12.3.0 |
| 2014-09 | RAN5#64 | R5-144144 | 0134 | - | Add Test Tolerance Analyses for TS 37.571-1 Test Cases 10.3 and 10.4 | 12.2.0 | 12.3.0 |
| 2014-09 | RAN5#64 | R5-144146 | 0135 | - | Add Test Tolerance Analyses for TS 37.571-1 Test Cases 10.3A and 10.4A | 12.2.0 | 12.3.0 |
| 2014-09 | RAN5#64 | R5-144290 | 0136 | - | Add Test Tolerance analysis for TS 36.521-3 Test case 8.3.6 | 12.2.0 | 12.3.0 |
| 2014-09 | RAN5#64 | R5-144292 | 0137 | - | Add Test Tolerance analysis for TS 36.521-3 Test case 8.5.6 | 12.2.0 | 12.3.0 |
| 2014-09 | RAN5#64 | R5-144294 | 0138 | - | Update Test Tolerance analyses for TS 36.521-3 Test cases 8.3.3+8.4.3 | 12.2.0 | 12.3.0 |
| 2014-09 | RAN5#64 | R5-144834 | 0139 | - | Addition of test tolerance analysis for 36.521-3 test case 9.4.1, 9.4.2 and 9.4.3 | 12.2.0 | 12.3.0 |

History

| | Document history | | | | | | | | | |
|---------|------------------|------------|--|--|--|--|--|--|--|--|
| V12.3.0 | September 2014 | ublication | | | | | | | | |
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